

**Graduate Student Activities at the 2008 VLSI Test Symposium**  
**April 27<sup>th</sup> – May 1<sup>st</sup>, 2008**  
**Rancho Bernardo Inn**  
**San Diego, CA, USA**

As part of the 2008 VLSI Test Symposium, the TTTC Student Activities Committee is organizing two activities aiming to provide graduate students with an opportunity to disseminate their research and obtain visibility in the international test community. Ph.D. students graduating in 2008 are invited to participate in the first activity, namely the *Doctoral Thesis Award Contest*. All other graduate students (Ph.D. or M.S.) working on a test-related thesis are invited to participate in the second activity, namely the *Thesis Research Poster Session*.

The goal of these activities is to promote and strengthen the interaction between graduate students and the industrial community, as well as to serve as a process by which student work is exposed to and tested under real-life industrial needs. This is achieved by offering students the chance to present their work in a conference environment to academic and industrial test experts, who will evaluate and comment in terms of novelty and advancement of industrial practice.

Details of these two activities are provided below:

**1.) Call for Abstracts – Doctoral Thesis Award Contest**

Doctoral students who are expected to graduate in 2008 are invited to submit a one page abstract of their thesis (maximum 750 words). A second page is allowed for references and/or figures only. As the abstracts will undergo blind review, please submit a separate cover page with the student name and affiliation, the proposed title of the thesis, the expected date of graduation and an endorsement by the advisor (i.e. a signed statement that he/she supports the student's participation in the contest).

Since the purpose of this contest is for the student to gain exposure and feedback from the industry, the abstract should clearly address the following: i) define the problem and its relevance to industry, ii) describe existing industrial practices for solving the problem, and iii) explain the proposed methodology (and any pertinent case study) and how it advances the theory and/or practice in the particular field.

The abstracts will be reviewed by a panel of industrial and academic experts for the three issues outlined above. A set of finalists will be selected for the final round of the contest. This round includes a five minute slot for oral presentation and a five minute slot for Q&A / feedback, during a dedicated session at the IEEE VLSI Test Symposium (VTS'08), which will be held in San Diego, CA on April 27<sup>th</sup> – May 1<sup>st</sup>. The panel of experts will judge the presentations, and the winner of the contest will receive the 2008 TTTC Doctoral Thesis Award during the social event of the Symposium, to which all finalists will be invited. This award includes an honorarium and an invitation to submit a paper on the presented work to the IEEE Design & Test magazine!

WHAT: Doctoral Thesis Award Contest

WHO: Ph.D. students expected to graduate in 2008

HOW: Submit a one page abstract (maximum 750 words) for blind review and a cover letter that includes your name and affiliation and the endorsement of your advisor as two different PDF files to [yorgos.makris@yale.edu](mailto:yorgos.makris@yale.edu). Address any questions to the same e-mail. The abstract needs to address the three issues outlined above and emphasis will be given to the advancement of industrial practice as compared to current methodologies.

WHEN: Deadline for abstract submission: February 29, 2008  
Notification of finalists for VTS'08 contest: March 24, 2008

## 2.) Call for Abstracts – Thesis Research Poster Session.

Ph.D. and M.S. students who are engaged in their thesis research with an advisor are invited to submit a one page abstract of their research (maximum 750 words). The abstract must include the student's name and affiliation, the title of the research project and the name of the faculty advisor. On a second page, students must provide one or more figures that portray the key elements of their research. References can be provided with the abstract or on a third page if needed.

As is true for the **Doctoral Thesis Award Contest**, this forum is designed to give students the opportunity to interact and receive feedback from industry personnel. The abstract outlines the focus of their research, and the figure(s) provide a preview of the poster. The abstract and figures should clearly address the following: i) define the problem and its relevance to industry, ii) describe existing ideas and/or practices for solving the problem, and iii) explain the proposed methodology and its advantages/disadvantages over existing approaches.

The abstracts and figures submitted will be reviewed and approved by an oversight committee. Students selected for the poster session will be notified and asked to submit the poster as a pdf file for review. The poster can be designed as a single image or as a set of nine individual 8.5" by 11" pages. Students are expected to bring the poster fully assembled to the symposium.

A one hour time slot will be allocated at this year's IEEE VLSI Test Symposium (VTS'08) for students to present their posters. A panel of industrial and academic experts will be selected to interact with each of the presenters. Each presenter will be judged on the criteria given above, as well as on the quality of the presentation and appearance of the poster. The winner of the competition will receive the 2008 TTTC Thesis Research Poster Award during the social event of the Symposium and an honorarium.

WHAT: Thesis Research Poster Session

WHO: Any Ph.D. or M.S. students NOT participating in the Doctoral Thesis Award Contest

HOW: Submit a one page abstract (maximum 750 words), a single page with figures and optionally a third page for references as a single PDF file to [plusquel@umbc.edu](mailto:plusquel@umbc.edu). Address any questions to the same e-mail.

WHEN: Deadline for abstract submission: February 29, 2008  
Deadline for poster submission: March 24, 2008